Action-based learning system for teaching digital electronics and test
Ubar, Raimund-Johannes; Wuttke, Heinz-Dietrich Microelectronics education : proceedings of the 3rd European Workshop on Microelectronics Education : France, May 18AMP19, 2000 2000 / p. 107-110 : ill

Arvuti nööpaugus
Agur, Ustus Horisont 1976 / lk. 12-15 : ill https://www.ester.ee/record=b1072243*est http://www.digar.ee/id/nlib-digar:291330

BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia)
Rang, Toomas; **Min, Mart**; **Ubar, Raimund-Johannes** 1994

BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia)
1994 https://www.ester.ee/record=b2150914*est

BEC 2002 : proceedings of the 8th Biennial Baltic Electronics Conference : October 6-9, 2002, Tallinn, Estonia
Rang, Toomas 2002 http://www.ester.ee/record=b2150914*est

BEC 2004 : Baltic Electronics Conference : Post-Graduate Student Session : Tallinn University of Technology, October 3-6, 2004, Tallinn, Estonia
2004 https://www.ester.ee/record=b1982896*est

BEC 2004 : proceedings of the 9th Biennial Baltic Electronics Conference : October 3-6, 2004, Tallinn, Estonia
2004 http://www.ester.ee/record=b2150914*est

BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference
Rang, Toomas 2006 http://www.ester.ee/record=b2150914*est

BEC 2008 : 2008 International Biennial Baltic Electronics Conference : proceedings of the 11th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 6-8, 2008, Tallinn, Estonia
Rang, Toomas 2008 http://www.ester.ee/record=b2150914*est

BEC 2010 : 2010 12th Biennial Baltic Electronics Conference : proceedings of the 12th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 4-6, 2010, Tallinn, Estonia
Rang, Toomas 2010 http://www.ester.ee/record=b2150914*est

BEC 2012 : 2012 13th Biennial Baltic Electronics Conference : proceedings of the 13th Biennial Baltic Electronics Conference : October 3-5, 2012, Tallinn, Estonia
2012 http://www.ester.ee/record=b2150914*est

BEC 2014 : 2014 14th Biennial Baltic Electronics Conference : proceedings of the 14th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 6-8, 2014, Tallinn, Estonia
Rang, Toomas 2014 http://www.ester.ee/record=b2150914*est

BEC 2016 : 2016 15th Biennial Baltic Electronics Conference : proceedings of the 15th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 3-5, 2016, Tallinn, Estonia
Rang, Toomas 2016 http://www.ester.ee/record=b2150914*est

BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings
Rang, Toomas; **Min, Mart**; **Ubar, Raimund-Johannes** 1996 https://www.ester.ee/record=b2150914*est

BEC'98 : the 6th Biennial Conference on Electronics and Microsystems Technology, October 7-9, 1998, Tallinn, Estonia : proceedings
Rang, Toomas 1998 https://www.ester.ee/record=b2150914*est

CAD in the education of microelectronics at the Technical University of Budapest
Szekely, V.; Tarnay, K. Automation, simulation & measurement : ASM'91 : 3rd biennal conference, Tallinn, October 7-11, 1991. Section S / Tallinn Technical University 1992 / p. 146-151

[Christou, A. Integrating reliability into microelectronics manufacturing. Series on design and measurement in electronic engineering, edited by D.V.Morgan and H.L.Grubin. Wiley, Chichester, 1994. 349 p. : Book review]
Velmre, Enn Engineering applications of artificial intelligence 1996 / p. 97 https://www.ester.ee/record=b1200126*est

Computer aided simulation of dynamic behaviour of the I^{2}L flip-flop
Rang, Toomas Microelectronics '82 : proceedings of the 3. Microelectronics Conference of the Socialist Countries ; from 5.-7. May

1982, Siófok, Hungary 1982 / p. 153-154

DAC 2000 - 37th Design Automation Conference
Ellervee, Peeter A & A 2000 / 5, lk. 53-54 https://artiklid.elnet.ee/record=b1005204*est

DefSim: measurement environment for CMOS defects
Borejko, Tomasz; **Jutman, Artur**; Pleskacz, Witold A.; **Ubar, Raimund-Johannes** 2006 25th International Conference on Microelectronics : Belgrade, Serbia and Montenegro, 14-17 May 2006 : proceedings. Volume 2 2006 / p. 679-682 https://ieeexplore.ieee.org/document/1651048

DefSim-based exercises for studying defects in CMOS gates
Jutman, Artur; Pleskacz, Witold A.; **Boiko, Nikolai**; **Ubar, Raimund-Johannes** EWME 2006 proceedings : 6th International Workshop on Microelectronics Education : 8-9 June, 2006, Stockholm, Sweden 2006 / p. 23-26 : ill

Design and test technology for dependable systems-on-chip
2011 https://www.ester.ee/record=b4467408*est

Development of e-learning course: myths and reality
Rang, Toomas; **Rang, Galina** Symposium "Topical Problems of Education in the Field of Electrical and Power Engineering" : Kuressaare, Estonia, January 19-24, 2004 2004 / p. 9-11

Digitaalmikroelektroonika projekteerimine
Põldre, Jüri A & A 1998 / 4, lk. 14-16

Digitaalsüsteemide diagnostika
Ubar, Raimund-Johannes 2005 http://www.ester.ee/record=b2097071*est

Eesti mikroelektroonika osaleb maailma virtuaalses kaubamajas
Ubar, Raimund-Johannes Eesti Päevaleht 1998 / 12. veebr., Uus Meedia, lk. 6

E-learning environment in the area of digital microelectronics
Jutman, Artur; **Sudnitsõn, Aleksander**; **Ubar, Raimund-Johannes**; Wuttke, Heinz-Dietrich ITHET 2004 : proceedings of the Fifth International Conference on Information Technology based Higher Education and Training : 31 May - 2 June, 2004, Istanbul, Turkey 2004 / p. 278-283 : ill

European Test Symposium : ETS 2005 : 22-25 May 2005, Tallinn, Estonia : proceedings
Cantarella, JD 2005 https://www.ester.ee/record=b2300865*est

Exercises. Final test questions : supplementary material in the course "Microelectronics"
Rang, Toomas 2003 https://www.ester.ee/record=b1766979*est

Flexible controller for educational robot kit
Ruberg, Priit; **Guitar, Aivar**; **Ellervee, Peeter** 2015 International Conference on Microelectronic Systems Education : MSE '15 : Pittsburgh, PA, May 20-21, 2015 2015 / p. 17-20 : ill http://dx.doi.org/10.1109/MSE.2015.7160007

Formulation and aerosol jet printing of nickel nanoparticle ink for high-temperature microelectronic applications and patterned graphene growth
McKibben, Nicholas; Curtis, Michael; Maryon, Olivia; Sawyer, Mone't; **Lazouskaya, Maryna**; Eixenberger, Josh; Deng, Zhangxian; Estrada, David ACS Applied Electronic Materials 2024 / p. 748 - 760 https://doi.org/10.1021/acsaelm.3c01175 Journal metrics at Scopus Article at Scopus Journal metrics at WOS Article at WOS

Four years of System-on-Chip curricula
Kruus, Margus; **Ellervee, Peeter** EWME 2006 proceedings : 6th International Workshop on Microelectronics Education : 8-9 June, 2006, Stockholm, Sweden 2006 / p. 88-91

Informal Digest of Papers : 10 IEEE European Test Symposium : Tallinn, Estonia, May 22-25, 2005
2005 https://www.ester.ee/record=b2055139*est

Inseneriharidus mikroelektroonika ajastul
Ubar, Raimund-Johannes Tehnikaülikool 1998 / 16. nov., lk. 6

Integraalskeemide projekteerimine : metoodiline juhend
1988 https://www.ester.ee/record=b1239938*est

Kas Eestil on vaja oma mikroelektroonikat?

Ubar, Raimund-Johannes Arvutimaailm 1993 / 2, lk. 46-47

Kümme korda aeglasem: Venemaa kasutab Hiina protsessorit, kuna lääne omi pole saada ja enda omad veel ei tööta [Võrguväljaanne]
Einama, Kaido postimees.ee 2022 10 korda aeglasem: Venemaa kasutab Hiina protsessorit, kuna lääne omi pole saada ja enda omad veel ei tööta

Mikro- und Feinwerktechnik in Lehre und Forschung an der TU Tallinn
Ajaots, Maido Zukunftsaspekte der Feinwerktechnik und Mikrotechnik in Lehre, Forschung und Industriekooperationen : 15. Internationales Kolloquium Feinwerktechnik, 1995 : 25. und 26. September 1995 in Mainz 1995 / S. 46-52
https://www.ester.ee/record=b1050005*est

Mikroelektroonika : laboratoorsete tööde juhend erialade 0701 ja 0612 üliõpilastele
1991 https://www.ester.ee/record=b1195431*est

Mikroelektroonika kiipide testimise tarkvara turbo-tester : kommentaar Eesti Teaduste Akadeemia Bernhard Schmidti preemia pälvinud tööle
Raik, Jaan Tallinna Tehnikaülikooli aastaraamat 2007 2008 / lk. 275-278

Mikroelektroonika laboratoorsete tööde juhend erialade 0701 ja 0612 üliõpilastele
1986 https://www.ester.ee/record=b1262234*est

Mikroelektroonika on muutumas nanoelektroonikaks
Krustok, Jüri Eesti Päevaleht 1996 / 24. apr., lk. 7

Monitoring patient movement velocity using passive infrared sensor information
Ehala, Johannes; **Astapov, Sergei** Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK seitsmenda aastakonverentsi artiklite kogumik : 15.-16. novembril 2013, Haapsalu 2013 / p. 21-24 : ill

Näidisülesanded. Test : abimaterjal ainele "Mikroelektroonika"
2003 http://www.ester.ee/record=b1766976*est

On model fitting methods for modeling polymer cure kinetics in microelectronics assembly applications
Tilford, T.; Morris, J.E.; **Ferenets, Marju**; Rajaguru, P.R.; Pavuluri, S.K.; Desmulliez, M.P.Y.; Bailey, C. 3rd Electronic System-Integration Technology Conference (ESTC) : Berlin, 13-16 Sept. 2010 : proceedings 2010 / [6] p.: ill
https://www.semanticscholar.org/paper/On-model-fitting-methods-for-modeling-polymer-cure-Tilford-Morris/58dd0553e4c835d51e54f1a932d2eec27f2cfed1

Pooljuhtkomponentide simuleerimine arvutil : laboratoorse töö juhend
2003 http://www.ester.ee/record=b1766958*est

Pooljuhtstruktuuride tööpõhimõtted. Struktuuride realisatsioonid kristallis : abimaterjal ainele "Mikroelektroonika"
2003 http://www.ester.ee/record=b1782563*est

Preface
Ubar, Raimund-Johannes; **Raik, Jaan**; Vierhaus, Heinrich Theodor Design and test technology for dependable systems-on-chip 2011 / p. xxii-xxviii

Principles of semiconductor structures. Realisation of structures in crystals : supplementary lecture material in the subject "Microelectronics"
Rang, Toomas 2003 http://www.ester.ee/record=b1782565*est

Proceedings of the 2012 IEEE 15th International Symposium on Design and Diagnostics of Electronic Circuits & Systems (DDECS) : April 18-20, 2012 Tallinn, Estonia
2012 http://www.ester.ee/record=b2777270*est

Selective Laser Melting Of Combustion Synthesized 2Mo-Cu and 3Cu-Mo Composites
Minasyan, Tatevik; **Aydinyan, Sofiya**; Kharatyan, Suren SHS 2017 : XIV International Symposium On Self-Propagating High Temperature Synthesis, September 25-28, 2017, Tblisi, Georgia : Book of Abstracts 2017 / p. 155−156 : ill
http://mmi.ge/uploads/files/2017-10/1507298270_book-of-abstracts-shs-2017.pdf

Self-testing of pipe-lined signal processing architectures at-speed
Gorev, Maksim; **Ubar, Raimund-Johannes**; **Ellervee, Peeter** Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK seitsmenda aastakonverentsi artiklite kogumik : 15.-16. novembril 2013, Haapsalu 2013 / p. 25-28 : ill

Simulation of semiconductor components on PC-s : instruction for laboratory work

Kurel, Raido 2003 http://www.ester.ee/record=b1766967*est

Special issue "Advanced hardware implementations for IoT systems and applications"
2022 https://www.mdpi.com/journal/electronics/special_issues/Hardware_IoT

10th IEEE European Test Symposium
Ubar, Raimund-Johannes; Prinetto, Paolo; **Raik, Jaan** IEEE journal of design & test of computers 2005 / p. 480-481 : phot http://dx.doi.org/10.1109/MDT.2005.106

The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings
Rang, Toomas 2000 https://www.ester.ee/record=b2150914*est

2023 IEEE Nordic Circuits and Systems Conference (NORCAS) : 31 October-November 1, 2023 Aalborg, Denmark : proceedings in IEEE Xplore
2023 https://researchr.org/publication/norcas-2023

Uued tuuled digitaalses fotograafias
Krustok, Jüri Tehnikamaailm 2003 / 10, lk. 50-51 https://artiklid.elnet.ee/record=b1043659*est

Virtual laboratory for research in dependable microelectronics
Diener, Karl-Heinz; Elst, G.; Gramatova, Elena; Kuzmicz, W.; Peng, Z.; **Ubar, Raimund-Johannes** The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings 2000 / p. 217-220 : ill

Алгоритмы цифрового усреднения сигналов и их реализация микроэлектронным фильтром
Logunov, Gennadi; **Sillamaa, Hanno** Методы и микроэлектронные средства цифрового преобразования и обработки сигналов : тезисы докладов конференциию, Т. 2 1983 / с. 174-176 https://www.ester.ee/record=b3715053*est

Влияние технологического микроклимата на качество изделий микроэлектроники
Kaipoksin, L.; Puusepp, Ü.; **Rätsep, Ülo**; Teevet, J.-T. Электронная промышленность : ЭП : научно-технический сборник 1983 / с. 76-79 : илл https://www.ester.ee/record=b1802011*est

Исследование и разработка методов тестового диагностирования дискретных систем : автореферат ... доктора технических наук (05.13.13)
Ubar, Raimund-Johannes 1986 https://www.ester.ee/record=b1564280*est

Микроэлектроника : руководство к лабораторным работам для студентов специальностей 0701, 0612
Laansoo, Ants 1985 https://www.ester.ee/record=b1253963*est

О влиянии электронно-упрочного рассеяния на коэффициент передачи лико микроэлектронного биполярного транзистора
Velmre, Enn; **Udal, Andres** Математическое моделирование физических процессов в полупроводниках и полупроводниковых приборах : тезисы докладов II всесоюзного совещания (г. Ярославль, сентябрь 1988 г.) 1988 / с. 40

Решение задач проектирования тестов микроэлектронных устройств при помощи АГ
Ubar, Raimund-Johannes Тезисы докл. всесоюзн. школы-семинара "Диагностика, надежность контроль" 1990 / с. 65